S1: AR<0.25% @ 355 nm, AOI=0 deg S2: AR<0.25% @ 355 nm, AOI=0 deg

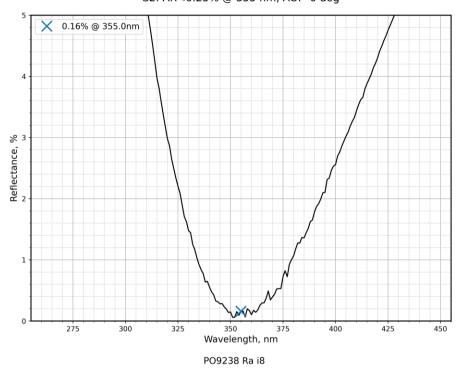


Fig. 1.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS:

YOUR SIDEKICK FOR LASER OPTICS DEVELOPMENT

S1: AR<0.25% @ 355 nm, AOI=0 deg S2: AR<0.25% @ 355 nm, AOI=0 deg

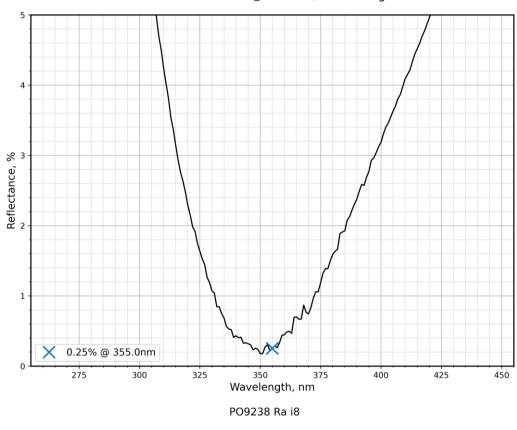


Fig. 2.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: